

<b>Notice of References Cited</b>	Application/Control No. 10/657,495	Applicant(s)/Patent Under Reexamination LAI, YU-CHIN	
	Examiner Helen L. Pezzuto	Art Unit 1713	Page 1 of 1

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	K	US-			
	L	US-			
	M	US-			

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	U	Stiller et al. Proceeding of SPIE (2003), 5122, 173-178.
	V	Sabi et al. Japanese Journal of Applied Physics, Part I: (2001), 40(3B), 1613-1618.
	W	Adameck et al. Applied Physics Letters (1998), 73(20), 2884-2886. □□
	X	Hill et al. Journal of Applied Physics (1991), 70(8), 4649-51.

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.